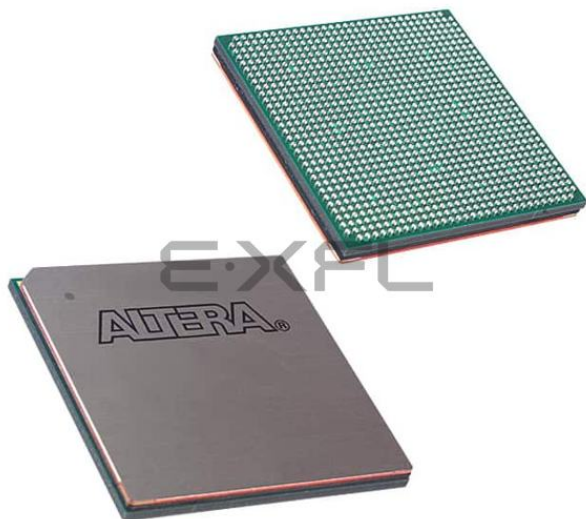




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Understanding **Embedded - FPGAs (Field Programmable Gate Array)**

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Obsolete
Number of LABs/CLBs	5712
Number of Logic Elements/Cells	57120
Total RAM Bits	5215104
Number of I/O	773
Number of Gates	-
Voltage - Supply	1.425V ~ 1.575V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	1020-BBGA
Supplier Device Package	1020-FBGA (33x33)
Purchase URL	https://www.e-xfl.com/product-detail/intel/ep1s60f1020c6

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Typographic Conventions

This document uses the typographic conventions shown below.

Visual Cue	Meaning
Bold Type with Initial Capital Letters	Command names, dialog box titles, checkbox options, and dialog box options are shown in bold, initial capital letters. Example: Save As dialog box.
bold type	External timing parameters, directory names, project names, disk drive names, filenames, filename extensions, and software utility names are shown in bold type. Examples: f_{MAX} , lqdesigns directory, d: drive, chiptrip.gdf file.
<i>Italic Type with Initial Capital Letters</i>	Document titles are shown in italic type with initial capital letters. Example: <i>AN 75: High-Speed Board Designs</i> .
<i>Italic type</i>	Internal timing parameters and variables are shown in italic type. Examples: <i>t_{PIA}</i> , <i>n + 1</i> . Variable names are enclosed in angle brackets (< >) and shown in italic type. Example: <file name>, <project name>.pof file.
Initial Capital Letters	Keyboard keys and menu names are shown with initial capital letters. Examples: Delete key, the Options menu.
“Subheading Title”	References to sections within a document and titles of on-line help topics are shown in quotation marks. Example: “Typographic Conventions.”
Courier type	Signal and port names are shown in lowercase Courier type. Examples: data1, tdi, input. Active-low signals are denoted by suffix n, e.g., resetn. Anything that must be typed exactly as it appears is shown in Courier type. For example: c:\qdesigns\tutorial\chiptrip.gdf. Also, sections of an actual file, such as a Report File, references to parts of files (e.g., the AHDL keyword SUBDESIGN), as well as logic function names (e.g., TRI) are shown in Courier.
1., 2., 3., and a., b., c., etc.	Numbered steps are used in a list of items when the sequence of the items is important, such as the steps listed in a procedure.
	Bullets are used in a list of items when the sequence of the items is not important.
	The checkmark indicates a procedure that consists of one step only.
	The hand points to information that requires special attention.
	The angled arrow indicates you should press the Enter key.
	The feet direct you to more information on a particular topic.

Table 2–2 shows the Stratix device’s routing scheme.

Table 2–2. Stratix Device Routing Scheme																	
Source	Destination																
	LUT Chain	Register Chain	Local Interconnect	Direct Link Interconnect	R4 Interconnect	R8 Interconnect	R24 Interconnect	C4 Interconnect	C8 Interconnect	C16 Interconnect	LE	M512 RAM Block	M4K RAM Block	M-RAM Block	DSP Blocks	Column IOE	Row IOE
LUT Chain											✓						
Register Chain											✓						
Local Interconnect											✓	✓	✓	✓	✓	✓	✓
Direct Link Interconnect			✓														
R4 Interconnect			✓		✓		✓	✓		✓							
R8 Interconnect			✓			✓			✓								
R24 Interconnect					✓		✓	✓		✓							
C4 Interconnect			✓		✓			✓									
C8 Interconnect			✓			✓			✓								
C16 Interconnect					✓		✓	✓		✓							
LE	✓	✓	✓	✓	✓	✓		✓	✓								
M512 RAM Block			✓	✓	✓	✓		✓	✓								
M4K RAM Block			✓	✓	✓	✓		✓	✓								
M-RAM Block								✓	✓								
DSP Blocks			✓	✓	✓	✓		✓	✓								
Column IOE				✓				✓	✓	✓							
Row IOE				✓		✓	✓	✓	✓	✓							

Figure 2–29. DSP Blocks Arranged in Columns

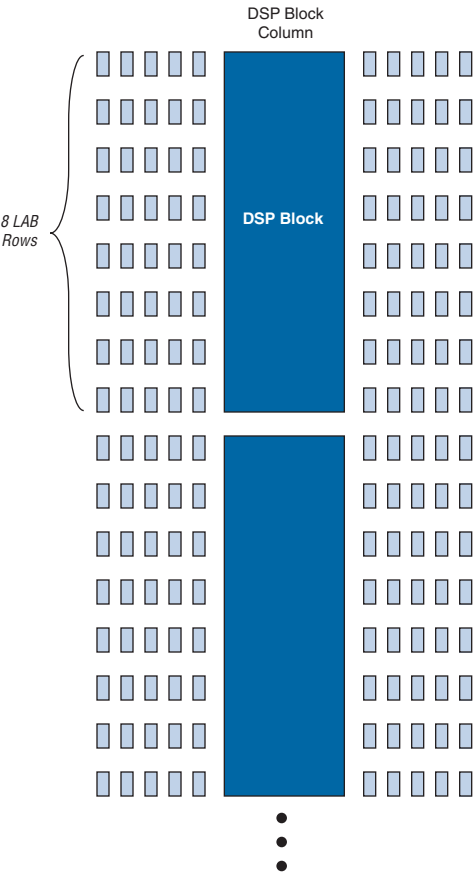
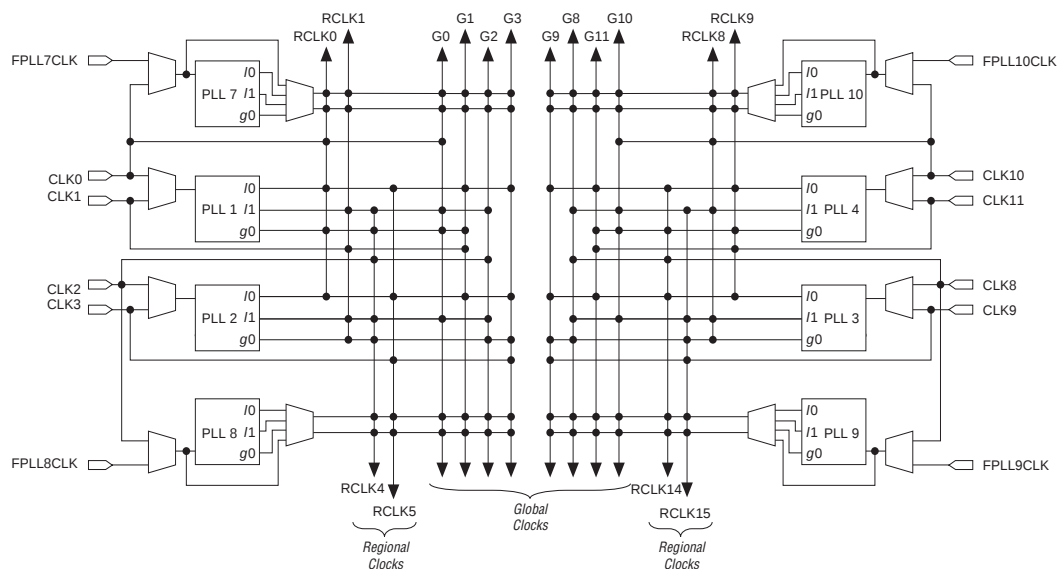


Figure 2–50 shows the global and regional clocking from the PLL outputs and the CLK pins.

Figure 2–50. Global & Regional Clock Connections from Side Pins & Fast PLL Outputs *Note (1), (2)*



Notes to Figure 2–50:

- (1) PLLs 1 to 4 and 7 to 10 are fast PLLs. PLLs 5, 6, 11, and 12 are enhanced PLLs.
- (2) The global or regional clocks in a fast PLL's quadrant can drive the fast PLL input. A pin or other PLL must drive the global or regional source. The source cannot be driven by internally generated logic before driving the fast PLL.

Figure 2–51 shows the global and regional clocking from enhanced PLL outputs and top CLK pins.

Table 2–26. External RAM Support in EP1S60 & EP1S80 Devices

DDR Memory Type	I/O Standard	Maximum Clock Rate (MHz)		
		-5 Speed Grade	-6 Speed Grade	-7 Speed Grade
DDR SDRAM (1), (2)	SSTL-2	167	167	133
DDR SDRAM - side banks (2), (3)	SSTL-2	150	133	133
QDR SRAM (4)	1.5-V HSTL	133	133	133
QDRII SRAM (4)	1.5-V HSTL	167	167	133
ZBT SRAM (5)	LVTTL	200	200	167

Notes to Table 2–26:

- (1) These maximum clock rates apply if the Stratix device uses DQS phase-shift circuitry to interface with DDR SDRAM. DQS phase-shift circuitry is only available in the top and bottom I/O banks (I/O banks 3, 4, 7, and 8).
- (2) For more information on DDR SDRAM, see AN 342: *Interfacing DDR SDRAM with Stratix & Stratix GX Devices*.
- (3) DDR SDRAM is supported on the Stratix device side I/O banks (I/O banks 1, 2, 5, and 6) without dedicated DQS phase-shift circuitry. The read DQS signal is ignored in this mode. Numbers are preliminary.
- (4) For more information on QDR or QDRII SRAM, see AN 349: *QDR SRAM Controller Reference Design for Stratix & Stratix GX Devices*.
- (5) For more information on ZBT SRAM, see AN 329: *ZBT SRAM Controller Reference Design for Stratix & Stratix GX Devices*.

In addition to six I/O registers and one input latch in the IOE for interfacing to these high-speed memory interfaces, Stratix devices also have dedicated circuitry for interfacing with DDR SDRAM. In every Stratix device, the I/O banks at the top (I/O banks 3 and 4) and bottom (I/O banks 7 and 8) of the device support DDR SDRAM up to 200 MHz. These pins support DQS signals with DQ bus modes of $\times 8$, $\times 16$, or $\times 32$.

Table 2–27 shows the number of DQ and DQS buses that are supported per device.

Table 2–27. DQS & DQ Bus Mode Support (Part 1 of 2) Note (1)

Device	Package	Number of $\times 8$ Groups	Number of $\times 16$ Groups	Number of $\times 32$ Groups
EP1S10	672-pin BGA	12 (2)	0	0
	672-pin FineLine BGA			
	484-pin FineLine BGA 780-pin FineLine BGA	16 (3)	0	4
EP1S20	484-pin FineLine BGA	18 (4)	7 (5)	4
	672-pin BGA 672-pin FineLine BGA	16 (3)	7 (5)	4
	780-pin FineLine BGA	20	7 (5)	4

The output levels are compatible with systems of the same voltage as the power supply (i.e., when V_{CCIO} pins are connected to a 1.5-V power supply, the output levels are compatible with 1.5-V systems). When V_{CCIO} pins are connected to a 3.3-V power supply, the output high is 3.3 V and is compatible with 3.3-V or 5.0-V systems.

Table 2–36 summarizes Stratix MultiVolt I/O support.

Table 2–36. Stratix MultiVolt I/O Support <i>Note (1)</i>										
V_{CCIO} (V)	Input Signal (5)					Output Signal (6)				
	1.5 V	1.8 V	2.5 V	3.3 V	5.0 V	1.5 V	1.8 V	2.5 V	3.3 V	5.0 V
1.5	✓	✓	✓ (2)	✓ (2)		✓				
1.8	✓ (2)	✓	✓ (2)	✓ (2)		✓ (3)	✓			
2.5			✓	✓		✓ (3)	✓ (3)	✓		
3.3			✓ (2)	✓	✓ (4)	✓ (3)	✓ (3)	✓ (3)	✓	✓

Notes to Table 2–36:

- (1) To drive inputs higher than V_{CCIO} but less than 4.1 V, disable the PCI clamping diode. However, to drive 5.0-V inputs to the device, enable the PCI clamping diode to prevent V_I from rising above 4.0 V.
- (2) The input pin current may be slightly higher than the typical value.
- (3) Although V_{CCIO} specifies the voltage necessary for the Stratix device to drive out, a receiving device powered at a different level can still interface with the Stratix device if it has inputs that tolerate the V_{CCIO} value.
- (4) Stratix devices can be 5.0-V tolerant with the use of an external resistor and the internal PCI clamp diode.
- (5) This is the external signal that is driving the Stratix device.
- (6) This represents the system voltage that Stratix supports when a V_{CCIO} pin is connected to a specific voltage level. For example, when V_{CCIO} is 3.3 V and if the I/O standard is LVTTTL/LVCMOS, the output high of the signal coming out from Stratix is 3.3 V and is compatible with 3.3-V or 5.0-V systems.

High-Speed Differential I/O Support

Stratix devices contain dedicated circuitry for supporting differential standards at speeds up to 840 Mbps. The following differential I/O standards are supported in the Stratix device: LVDS, LVPECL, HyperTransport, and 3.3-V PCML.

There are four dedicated high-speed PLLs in the EP1S10 to EP1S25 devices and eight dedicated high-speed PLLs in the EP1S30 to EP1S80 devices to multiply reference clocks and drive high-speed differential SERDES channels.

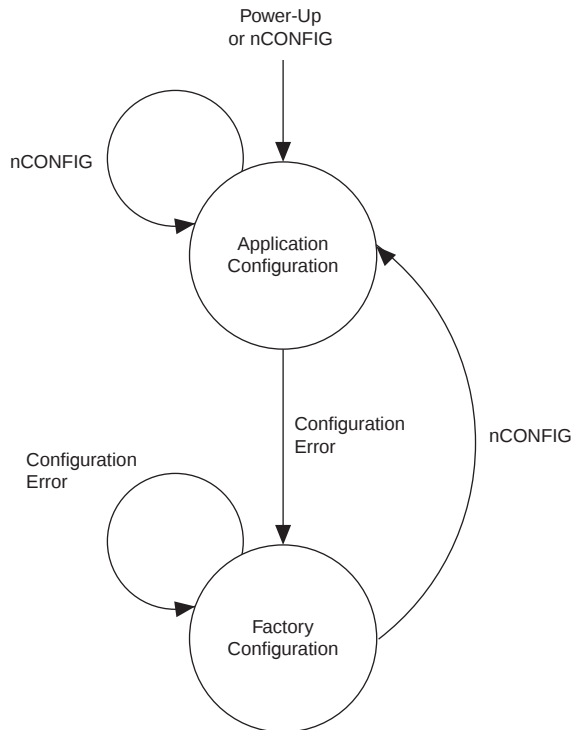


See the Stratix device pin-outs at www.altera.com for additional high speed DIFFIO pin information for Stratix devices.

Local Update Mode

Local update mode is a simplified version of the remote update. This feature is intended for simple systems that need to load a single application configuration immediately upon power up without loading the factory configuration first. Local update designs have only one application configuration to load, so it does not require a factory configuration to determine which application configuration to use. Figure 3–4 shows the transition diagram for local update mode.

Figure 3–4. Local Update Transition Diagram



Stratix Automated Single Event Upset (SEU) Detection

Stratix devices offer on-chip circuitry for automated checking of single event upset (SEU) detection. FPGA devices that operate at high elevations or in close proximity to earth's North or South Pole require periodic checks to ensure continued data integrity. The error detection cyclic redundancy check (CRC) feature controlled by the **Device & Pin Options** dialog box in the Quartus II software uses a 32-bit CRC circuit to ensure data reliability and is one of the best options for mitigating SEU.

Figure 3–5. External Temperature-Sensing Diode

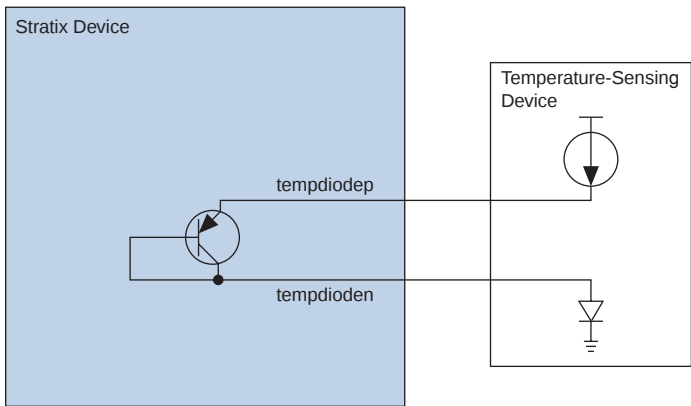


Table 3–6 shows the specifications for bias voltage and current of the Stratix temperature sensing diode.

Table 3–6. Temperature-Sensing Diode Electrical Characteristics				
Parameter	Minimum	Typical	Maximum	Unit
$I_{\text{BIAS high}}$	80	100	120	μA
$I_{\text{BIAS low}}$	8	10	12	μA
$V_{\text{BP}} - V_{\text{BN}}$	0.3		0.9	V
V_{BN}		0.7		V
Series resistance			3	W

Table 4–47. DSP Block Internal Timing Microparameters (Part 2 of 2)

Symbol	-5		-6		-7		-8		Unit
	Min	Max	Min	Max	Min	Max	Min	Max	
$t_{\text{PIPE2OUTREG2ADD}}$		2,002		2,203		2,533		2,980	ps
$t_{\text{PIPE2OUTREG4ADD}}$		2,899		3,189		3,667		4,314	ps
t_{PD9}		3,709		4,081		4,692		5,520	ps
t_{PD18}		4,795		5,275		6,065		7,135	ps
t_{PD36}		7,495		8,245		9,481		11,154	ps
t_{CLR}	450		500		575		676		ps
t_{CLKHL}	1,350		1,500		1,724		2,029		ps

Table 4–48. M512 Block Internal Timing Microparameters

Symbol	-5		-6		-7		-8		Unit
	Min	Max	Min	Max	Min	Max	Min	Max	
t_{M512RC}		3,340		3,816		4,387		5,162	ps
t_{M512WC}		3,138		3,590		4,128		4,860	ps
$t_{\text{M512WERESU}}$	110		123		141		166		ps
$t_{\text{M512WEREH}}$	34		38		43		51		ps
$t_{\text{M512CLKENSU}}$	215		215		247		290		ps
$t_{\text{M512CLKENH}}$	–70		–70		–81		–95		ps
$t_{\text{M512DATASU}}$	110		123		141		166		ps
$t_{\text{M512DATAH}}$	34		38		43		51		ps
$t_{\text{M512WADDRSU}}$	110		123		141		166		ps
$t_{\text{M512WADDRH}}$	34		38		43		51		ps
$t_{\text{M512RADDRSU}}$	110		123		141		166		ps
$t_{\text{M512RADDRH}}$	34		38		43		51		ps
$t_{\text{M512DATACO1}}$		424		472		541		637	ps
$t_{\text{M512DATACO2}}$		3,366		3,846		4,421		5,203	ps
$t_{\text{M512CLKHL}}$	1,000		1,111		1,190		1,400		ps
t_{M512CLR}	170		189		217		255		ps

Table 4–65. EP1S20 External I/O Timing on Row Pins Using Regional Clock Networks *Note (1)*

Parameter	-5 Speed Grade		-6 Speed Grade		-7 Speed Grade		-8 Speed Grade		Unit
	Min	Max	Min	Max	Min	Max	Min	Max	
t_{INSU}	1.815		1.967		2.258		NA		ns
t_{INH}	0.000		0.000		0.000		NA		ns
t_{OUTCO}	2.633	5.235	2.663	5.595	2.663	6.070	NA	NA	ns
t_{XZ}	2.660	5.289	2.660	5.651	2.660	6.138	NA	NA	ns
t_{ZX}	2.660	5.289	2.660	5.651	2.660	6.138	NA	NA	ns
t_{INSUPLL}	1.060		1.112		1.277		NA		ns
t_{INHPLL}	0.000		0.000		0.000		NA		ns
t_{OUTCOPLL}	1.325	2.770	1.325	2.908	1.325	2.978	NA	NA	ns
t_{XZPLL}	1.352	2.824	1.352	2.964	1.352	3.046	NA	NA	ns
t_{ZXPLL}	1.352	2.824	1.352	2.964	1.352	3.046	NA	NA	ns

Table 4–66. EP1S20 External I/O Timing on Row Pins Using Global Clock Networks *Note (1)*

Parameter	-5 Speed Grade		-6 Speed Grade		-7 Speed Grade		-8 Speed Grade		Unit
	Min	Max	Min	Max	Min	Max	Min	Max	
t_{INSU}	1.742		1.887		2.170		NA		ns
t_{INH}	0.000		0.000		0.000		NA		ns
t_{OUTCO}	2.674	5.308	2.674	5.675	2.674	6.158	NA	NA	ns
t_{XZ}	2.701	5.362	2.701	5.731	2.701	6.226	NA	NA	ns
t_{ZX}	2.701	5.362	2.701	5.731	2.701	6.226	NA	NA	ns
t_{INSUPLL}	1.353		1.418		1.613		NA		ns
t_{INHPLL}	0.000		0.000		0.000		NA		ns
t_{OUTCOPLL}	1.158	2.447	1.158	2.602	1.158	2.642	NA	NA	ns
t_{XZPLL}	1.185	2.531	1.158	2.602	1.185	2.710	NA	NA	ns
t_{ZXPLL}	1.185	2.531	1.158	2.602	1.185	2.710	NA	NA	ns

Note to Tables 4–61 to 4–66:

(1) Only EP1S25, EP1S30, and EP1S40 have a speed grade of -8.

Table 4–75. EP1S30 External I/O Timing on Column Pins Using Global Clock Networks (Part 2 of 2)

Parameter	-5 Speed Grade		-6 Speed Grade		-7 Speed Grade		-8 Speed Grade		Unit
	Min	Max	Min	Max	Min	Max	Min	Max	
t_{XZ}	2.754	5.406	2.754	5.848	2.754	6.412	2.754	7.159	ns
t_{ZX}	2.754	5.406	2.754	5.848	2.754	6.412	2.754	7.159	ns
$t_{INSUPLL}$	1.265		1.236		1.403		1.756		ns
t_{INHPLL}	0.000		0.000		0.000		0.000		ns
$t_{OUTCOPLL}$	1.068	2.302	1.068	2.483	1.068	2.510	1.068	2.423	ns
t_{XZPLL}	1.008	2.176	1.008	2.351	1.008	2.386	1.008	2.308	ns
t_{ZXPLL}	1.008	2.176	1.008	2.351	1.008	2.386	1.008	2.308	ns

Table 4–76. EP1S30 External I/O Timing on Row Pins Using Fast Regional Clock Networks

Parameters	-5 Speed Grade		-6 Speed Grade		-7 Speed Grade		-8 Speed Grade		Unit
	Min	Max	Min	Max	Min	Max	Min	Max	
t_{INSU}	2.616		2.808		3.223		3.797		ns
t_{INH}	0.000		0.000		0.000		0.000		ns
t_{OUTCO}	2.542	5.114	2.542	5.502	2.542	5.965	2.542	6.581	ns
t_{XZ}	2.569	5.168	2.569	5.558	2.569	6.033	2.569	6.663	ns
t_{ZX}	2.569	5.168	2.569	5.558	2.569	6.033	2.569	6.663	ns

Tables 4–91 through 4–96 show the external timing parameters on column and row pins for EP1S80 devices.

Table 4–91. EP1S80 External I/O Timing on Column Pins Using Fast Regional Clock Networks *Note (1)*

Parameter	-5 Speed Grade		-6 Speed Grade		-7 Speed Grade		-8 Speed Grade		Unit
	Min	Max	Min	Max	Min	Max	Min	Max	
t_{INSU}	2.328		2.528		2.900		NA		ns
t_{INH}	0.000		0.000		0.000		NA		ns
t_{OUTCO}	2.422	4.830	2.422	5.169	2.422	5.633	NA	NA	ns
t_{XZ}	2.362	4.704	2.362	5.037	2.362	5.509	NA	NA	ns
t_{ZX}	2.362	4.704	2.362	5.037	2.362	5.509	NA	NA	ns

Table 4–92. EP1S80 External I/O Timing on Column Pins Using Regional Clock Networks *Note (1)*

Parameter	-5 Speed Grade		-6 Speed Grade		-7 Speed Grade		-8 Speed Grade		Unit
	Min	Max	Min	Max	Min	Max	Min	Max	
t_{INSU}	1.760		1.912		2.194		NA		ns
t_{INH}	0.000		0.000		0.000		NA		ns
t_{OUTCO}	2.761	5.398	2.761	5.785	2.761	6.339	NA	NA	ns
t_{XZ}	2.701	5.272	2.701	5.653	2.701	6.215	NA	NA	ns
t_{ZX}	2.701	5.272	2.701	5.653	2.701	6.215	NA	NA	ns
t_{INSUPLL}	0.462		0.606		0.785		NA		ns
t_{INHPLL}	0.000		0.000		0.000		NA		ns
t_{OUTCOPLL}	1.661	2.849	1.661	2.859	1.661	2.881	NA	NA	ns
t_{XZPLL}	1.601	2.723	1.601	2.727	1.601	2.757	NA	NA	ns
t_{ZXPLL}	1.601	2.723	1.601	2.727	1.601	2.757	NA	NA	ns

Table 4–97. Output Pin Timing Skew Definitions (Part 2 of 2)

Symbol	Definition
t_{LR_HIO}	Across all HIO banks (1, 2, 5, 6); across four similar type I/O banks
t_{TB_VIO}	Across all VIO banks (3, 4, 7, 8); across four similar type I/O banks
$t_{OVERALL}$	Output timing skew for all I/O pins on the device.

Notes to Table 4–97:

- (1) See Figure 4–5 on page 4–57.
- (2) See Figure 4–6 on page 4–58.

Table 4–98 shows the I/O skews when using the same global or regional clock to feed IOE registers in I/O banks around each device. These values can be used for calculating the timing budget on the output (write) side of a memory interface. These values already factor in the package skew.

Table 4–98. Output Skew for Stratix by Device Density

Symbol	Skew (ps) (1)		
	EP1S10 to EP1S30	EP1S40	EP1S60 & EP1S80
t_{SB_HIO}	90	290	500
t_{SB_VIO}	160	290	500
t_{SS_HIO}	90	460	600
t_{SS_VIO}	180	520	630
t_{LR_HIO}	150	490	600
t_{TB_VIO}	190	580	670
$t_{OVERALL}$	430	630	880

Note to Table 4–98:

- (1) The skew numbers in Table 4–98 account for worst case package skews.

Table 4–125. High-Speed I/O Specifications for Flip-Chip Packages (Part 2 of 4) Notes (1), (2)

Symbol	Conditions	-5 Speed Grade			-6 Speed Grade			-7 Speed Grade			-8 Speed Grade			Unit
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
f_{HCLK} (Clock frequency) (PCML) $f_{\text{HCLK}} = f_{\text{HSDR}} / W$	W = 4 to 30 (Serdes used)	10		100	10		100	10		77.75	10		77.75	MHz
	W = 2 (Serdes bypass)	50		200	50		200	50		150	50		150	MHz
	W = 2 (Serdes used)	150		200	150		200	150		155.5	150		155.5	MHz
	W = 1 (Serdes bypass)	100		250	100		250	100		200	100		200	MHz
	W = 1 (Serdes used)	300		400	300		400	300		311	300		311	MHz
f_{HSDR} Device operation (PCML)	J = 10	300		400	300		400	300		311	300		311	Mbps
	J = 8	300		400	300		400	300		311	300		311	Mbps
	J = 7	300		400	300		400	300		311	300		311	Mbps
	J = 4	300		400	300		400	300		311	300		311	Mbps
	J = 2	100		400	100		400	100		300	100		300	Mbps
	J = 1	100		250	100		250	100		200	100		200	Mbps
TCCS	All			200			200			300			300	ps

Table 4–129. Enhanced PLL Specifications for -7 Speed Grade (Part 2 of 2)

Symbol	Parameter	Min	Typ	Max	Unit
t_{OUTDUTY}	Duty cycle for external clock output (when set to 50%)	45		55	%
t_{JITTER}	Period jitter for external clock output (6)			± 100 ps for >200-MHz outclk ± 20 mUI for <200-MHz outclk	ps or mUI
$t_{\text{CONFIG5,6}}$	Time required to reconfigure the scan chains for PLLs 5 and 6			$289/f_{\text{SCANCLK}}$	
$t_{\text{CONFIG11,12}}$	Time required to reconfigure the scan chains for PLLs 11 and 12			$193/f_{\text{SCANCLK}}$	
t_{SCANCLK}	scanclk frequency (5)			22	MHz
t_{DLOCK}	Time required to lock dynamically (after switchover or reconfiguring any non-post-scale counters/delays) (7) (11)	(9)		100	μs
t_{LOCK}	Time required to lock from end of device configuration (11)	10		400	μs
f_{VCO}	PLL internal VCO operating range	300		600 (8)	MHz
t_{LSKEW}	Clock skew between two external clock outputs driven by the same counter		± 50		ps
t_{SKEW}	Clock skew between two external clock outputs driven by the different counters with the same settings		± 75		ps
f_{SS}	Spread spectrum modulation frequency	30		150	kHz
% spread	Percentage spread for spread spectrum frequency (10)	0.5		0.6	%
t_{ARESET}	Minimum pulse width on areset signal	10			ns

Table 4–130. Enhanced PLL Specifications for -8 Speed Grade (Part 1 of 3)

Symbol	Parameter	Min	Typ	Max	Unit
f_{IN}	Input clock frequency	3 (1), (2)		480	MHz
f_{INPFD}	Input frequency to PFD	3		420	MHz
f_{INDUTY}	Input clock duty cycle	40		60	%
f_{EINDUTY}	External feedback clock input duty cycle	40		60	%
t_{INJITTER}	Input clock period jitter			± 200 (3)	ps

Table 4–130. Enhanced PLL Specifications for -8 Speed Grade (Part 2 of 3)

Symbol	Parameter	Min	Typ	Max	Unit
$t_{\text{EINJITTER}}$	External feedback clock period jitter			± 200 (3)	ps
t_{FCOMP}	External feedback clock compensation time (4)			6	ns
f_{OUT}	Output frequency for internal global or regional clock	0.3		357	MHz
$f_{\text{OUT_EXT}}$	Output frequency for external clock (3)	0.3		369	MHz
t_{OUTDUTY}	Duty cycle for external clock output (when set to 50%)	45		55	%
t_{JITTER}	Period jitter for external clock output (6)			± 100 ps for >200-MHz outclk ± 20 mUI for <200-MHz outclk	ps or mUI
$t_{\text{CONFIG5,6}}$	Time required to reconfigure the scan chains for PLLs 5 and 6			$289/f_{\text{SCANCLK}}$	
$t_{\text{CONFIG11,12}}$	Time required to reconfigure the scan chains for PLLs 11 and 12			$193/f_{\text{SCANCLK}}$	
t_{SCANCLK}	scanclk frequency (5)			22	MHz
t_{DLOCK}	Time required to lock dynamically (after switchover or reconfiguring any non-post-scale counters/delays) (7) (11)	(9)		100	μs
t_{LOCK}	Time required to lock from end of device configuration (11)	10		400	μs
f_{VCO}	PLL internal VCO operating range	300		600 (8)	MHz

Table 4–130. Enhanced PLL Specifications for -8 Speed Grade (Part 3 of 3)

Symbol	Parameter	Min	Typ	Max	Unit
t_{LSKEW}	Clock skew between two external clock outputs driven by the same counter		± 50		ps
t_{SKEW}	Clock skew between two external clock outputs driven by the different counters with the same settings		± 75		ps
f_{SS}	Spread spectrum modulation frequency	30		150	kHz
% spread	Percentage spread for spread spectrum frequency (10)	0.5		0.6	%
t_{ARESET}	Minimum pulse width on areset signal	10			ns

Notes to Tables 4–127 through 4–130:

- (1) The minimum input clock frequency to the PFD (f_{IN}/N) must be at least 3 MHz for Stratix device enhanced PLLs.
- (2) Use this equation ($f_{OUT} = f_{IN} * ml(n \times \text{post-scale counter})$) in conjunction with the specified f_{INPFD} and f_{VCO} ranges to determine the allowed PLL settings.
- (3) See “Maximum Input & Output Clock Rates” on page 4–76.
- (4) t_{FCOMP} can also equal 50% of the input clock period multiplied by the pre-scale divider n (whichever is less).
- (5) This parameter is timing analyzed by the Quartus II software because the `scanc1k` and `scandata` ports can be driven by the logic array.
- (6) Actual jitter performance may vary based on the system configuration.
- (7) Total required time to reconfigure and lock is equal to $t_{DLOCK} + t_{CONFIG}$. If only post-scale counters and delays are changed, then t_{DLOCK} is equal to 0.
- (8) When using the spread-spectrum feature, the minimum VCO frequency is 500 MHz. The maximum VCO frequency is determined by the speed grade selected.
- (9) Lock time is a function of PLL configuration and may be significantly faster depending on bandwidth settings or feedback counter change increment.
- (10) Exact, user-controllable value depends on the PLL settings.
- (11) The LOCK circuit on Stratix PLLs does not work for industrial devices below -20C unless the PFD frequency > 200 MHz. See the *Stratix FPGA Errata Sheet* for more information on the PLL.

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